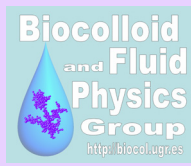




Nanoparticle deposits formed at driven contact lines



Carmen Lucía Moraila-Martínez, Miguel Cabrerizo-Vílchez and Miguel Ángel Rodríguez-Valverde

Biocolloid and Fluid Physics Group, Department of Applied Physics, University of Granada, E-18071 Spain

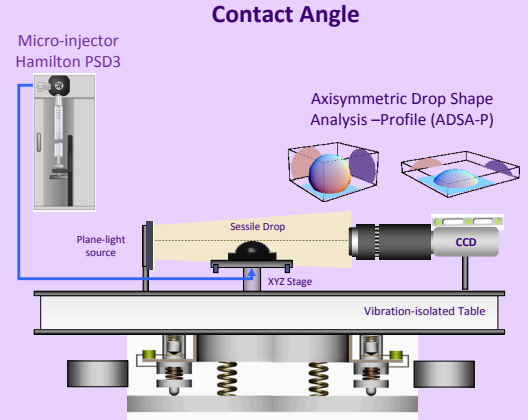
1 Motivation

- **Desiccation of colloidal suspension** drops appears in many applications such as coatings (paints, ink printing, paving), colloidal assembly/templating even biomedicine (diagnostics).
- Ring/stain formation of drying colloidal suspensions is mainly ruled by **contact line dynamics**. Receding contact lines are ubiquitous at evaporating drops but the time scale of the process is extremely long.
- In this work, we measured low-rate dynamic contact angles using a **non-linear variation of drop volume** in order to control the speed of the receding contact line and further to emulate the first stages of drop evaporation at shorter times.



2 Materials and Methods

- **Substrate :**
 - ✦ PMMA (Goodfellow)
- **Nanoparticles:**
 - ✦ Silica 12 nm (Klebosol) and 90 nm (homemade).
 - ✦ PMMA 108nm (microParticles GmbH).
- **Solute volume fraction:**
 - ✦ 0.5% to 3%
- **Drop volume:**
 - ✦ 220µl @ 25°C RH 50%

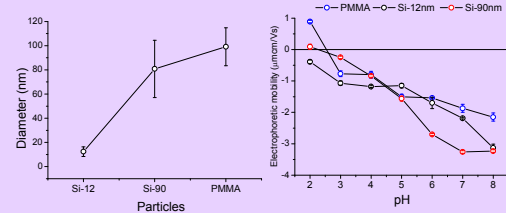
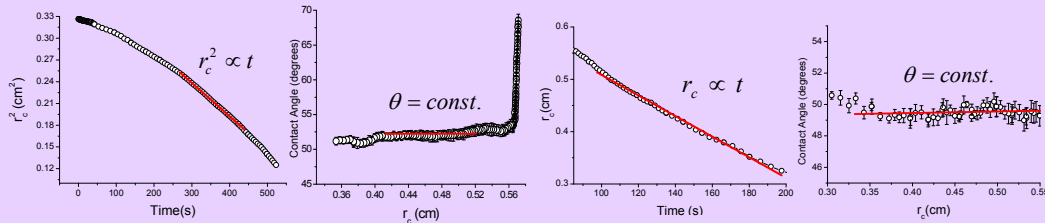


3 Results

Assisted drop evaporation (distilled water)

Uniform motion of the contact line (distilled water)

Particle characterization



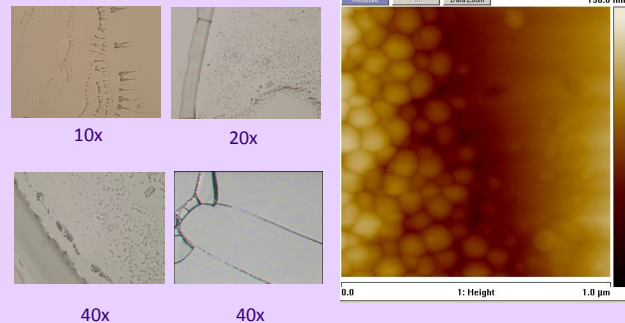
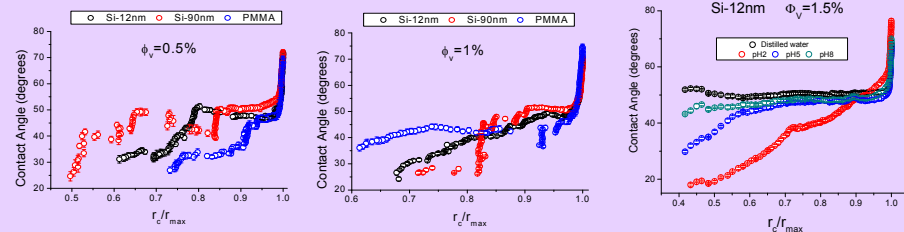
Assisted drop evaporation (nanoparticle drops pH=?)

Uniform motion of the contact line (nanoparticle drops pH=?)

Morphology of the nanoparticle deposits

Optical microscopy

AFM



4 Conclusions

- The first stages of drop evaporation have been emulated at shorter times.
- Stick-slip motion of receding nanoparticle drops is controlled by the interplay between van der Waals and electrostatic forces.
- The morphology of nanoparticle deposits is strongly related with the behaviour of the receding contact line.

5 References

[1] R.D. Deegan, O. Bakajin, T. F. Dupont, G. Huber, S. R. Nagel and T. A. Witten. *Phys Rev E* 62, pp 756-765 (2000).
 [2] E. Rio, A. Daerr, F. Lequeux, and L. Limat, *Langmuir* 22, pp 3186-3191 (2006).
 [3] H. Yildirim Erbil, G. McHale, S. M. Rowan, and M. I. Newton, *Langmuir*, 21, pp 7378-7385 (1999).
 [4] H. Tavana and A.W. Neumann, *Colloids and Surfaces A: Physicochemical and Engineering Aspects*, 282-283, pp 256-262 (2006).